RELIABILITY MONITOR

DS1000M-25 FEB '98 MONITOR-OMEDATA

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS1000	E3	9750	DD740614ABA	8 PIN PDIP	OMEDATA

PROCESS Single Poly, Single Metal 1.2 µ Standard Process

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: 60% Tuse: 55 °C
Ea: 0.7 Vuse: 5.5 Volts
β: 1

JOB NO	DESCRIPT	CONDITION		QUANTITY	READPOINT	UNITS	NO OF FAILS
P21467	INFANT LIFE	125°C, 7.0 VOLTS		234	48	HOUR	0
P21488	HIGH VOLTAGE LIFE	125°C, 7.0 VOLTS		77	336	HOUR	0
		125°C, 7.0 VOLTS		77	1000	HOUR	0
		TOTALS:	FAIL RATE (Fits):	30	DEVICE HRS: 3.08E+07		0
P21489	TEMP CYCLE	-55 TO 125°C		40	300	CYCL	0
				40	1000	CYCL	0
		TOTAL:					0
P21490	BIASED MOISTURE	85/85, 5.5 VOLTS		77	274	HOUR	0
				77	959	HOUR	0
		TOTAL:					0
P21491	AUTOCLAVE	121°C STEAM, UNBIASED		40	96	HOUR	0
		TOTAL:					0

RELIABILITY MONITOR

DS1210S JAN '98 MONITOR-HYUNDAI

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS1210	C1	9750	DN738347AAA	16 PIN SOIC	HYUNDAI-KOREA (HEI)

PROCESS Single Poly, Single Metal 3.0 µ POCL3 reFlow (3um only); FLASH E2PROM (all other tech. numbers)

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: 60% Tuse: 55 °C
Ea: 0.7 Vuse: 5.5 Volts
β: 1

JOB NO	DESCRIPT	CONDITION		QUANTITY	READPOINT	UNITS	NO OF FAILS
P21776	INFANT LIFE	125°C, 7.0 VOLTS		234	48	HOUR	0
P22233	HIGH VOLTAGE LIFE	125°C, 7.0 VOLTS		77	336	HOUR	0
		125°C, 7.0 VOLTS		77	1000	HOUR	0
		TOTALS:	FAIL RATE (Fits):	30	DEVICE HRS: 3.08E+07		0
P21287	HIGH TEMP STORAGE	125°C		238	24	HOUR	
	MOISTURE SOAK	85°C/85% R.H.		238	168	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE		238	3	PASS	0
		TOTAL:					0
P22234	TEMP CYCLE	-55 TO 125°C		40	300	CYCL	0
				40	1000	CYCL	0
		TOTAL:					0
P22236	AUTOCLAVE	121°C STEAM, UNBIASED		40	96	HOUR	0
		TOTAL:					0

RELIABILITY MONITOR

DS1210S APR '98 MONITOR - ANAM,K.

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS1210	C1	9811	DN752523AAC	16 PIN SOIC	ANAM-KOREA (AICL)

PROCESS Single Poly, Single Metal 3.0 µ POCL3 reFlow (3um only); FLASH E2PROM (all other tech. numbers)

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: 60% Tuse: 55 °C
Ea: 0.7 Vuse: 5.5 Volts
β: 1

JOB NO	DESCRIPT	CONDITION		QUANTITY	READPOINT	UNITS	NO OF FAILS
P22232	INFANT LIFE	125°C, 7.0 VOLTS		233	48	HOUR	0
P22262	HIGH VOLTAGE LIFE	125°C, 7.0 VOLTS		77	336	HOUR	0
		125°C, 7.0 VOLTS		77	1000	HOUR	0
		TOTALS:	FAIL RATE (Fits):	30	DEVICE HRS: 3.08E+07		0
P21895	HIGH TEMP STORAGE	125°C		238	24	HOUR	
	MOISTURE SOAK	85°C/85% R.H.		238	168	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE		238	3	PASS	0
		TOTAL:					0
P22263	TEMP CYCLE	-55 TO 125°C		38	400	CYCL	0
				38	1000	CYCL	0
		TOTAL:					0
P22265	AUTOCLAVE	121°C STEAM, UNBIASED		38	96	HOUR	0
		TOTAL:					0

RELIABILITY MONITOR

DS1232S JAN '98 MONITOR-HYUNDAI

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS1232	C1	9740	DL728793AAF	16 PIN SOIC	HYUNDAI-KOREA (HEI)

PROCESS Single Poly, Single Metal 3.0 µ Standard Process

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: 60% Tuse: 55 °C
Ea: 0.7 Vuse: 5.5 Volts
β: 1

JOB NO	DESCRIPT	CONDITION		QUANTITY	READPOINT	UNITS	NO OF FAILS
P21326	INFANT LIFE	125°C, 7.0 VOLTS		234	48	HOUR	0
P21403	HIGH VOLTAGE LIFE	125°C, 7.0 VOLTS		77	336	HOUR	0
		125°C, 7.0 VOLTS		77	1000	HOUR	0
		TOTALS:	FAIL RATE (Fits):	30	DEVICE HRS: 3.08E+07		0
P21246	HIGH TEMP STORAGE	125°C		238	24	HOUR	
	MOISTURE SOAK	85°C/85% R.H.		238	168	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE		238	3	PASS	0
		TOTAL:					0
P21404	TEMP CYCLE	-55 TO 125°C		40	300	CYCL	0
				40	1000	CYCL	0
		TOTAL:					0
P21405	BIASED MOISTURE	85/85, 5.5 VOLTS		77	274	HOUR	0
				77	959	HOUR	0
		TOTAL:					0
P21406	AUTOCLAVE	121°C STEAM, UNBIASED		40	96	HOUR	0
		TOTAL:					0

RELIABILITY MONITOR

DS1232S APR '98 MONITOR - ANAM,K.

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS1232	C1	9805	DN737280ABA	16 PIN SOIC	ANAM-KOREA (AICL)

PROCESS Single Poly, Single Metal 3.0 µ Standard Process

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: 60% Tuse: 55 °C
Ea: 0.7 Vuse: 5.5 Volts
β: 1

JOB NO	DESCRIPT	CONDITION		QUANTITY	READPOINT	UNITS	NO OF FAILS
P22047	INFANT LIFE	125°C, 7.0 VOLTS		234	48	HOUR	0
P22145	HIGH VOLTAGE LIFE	125°C, 7.0 VOLTS		77	336	HOUR	0
		125°C, 7.0 VOLTS		77	1000	HOUR	0
		TOTALS:	FAIL RATE (Fits):	30	DEVICE HRS: 3.08E+07		0
P21901	HIGH TEMP STORAGE	125°C		238	24	HOUR	
	MOISTURE SOAK	85°C/85% R.H.		238	168	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE		238	3	PASS	0
		TOTAL:					0
P22146	TEMP CYCLE	-55 TO 125°C		40	300	CYCL	0
				40	1000	CYCL	0
		TOTAL:					0
P22147	BIASED MOISTURE	85/85, 5.5 VOLTS		77	274	HOUR	0
				77	959	HOUR	0
		TOTAL:					0
P22148	AUTOCLAVE	121°C STEAM, UNBIASED		40	96	HOUR	0
		TOTAL:					0

RELIABILITY MONITOR

DS1233Z-10 JAN '98 MONITOR-CARSEM

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS1233	A5	9737	DM721164ABA	SOT-223	CARSEM

PROCESS Single Poly, Single Metal 1.2 µ Zero tempco poly

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: 60% Tuse: 55 °C
Ea: 0.7 Vuse: 5.5 Volts
β: 1

JOB NO	DESCRIPT	CONDITION		QUANTITY	READPOINT	UNITS	NO OF FAILS
P21396	INFANT LIFE	125°C, 7.0 VOLTS		229	48	HOUR	0
P21440	HIGH VOLTAGE LIFE	125°C, 7.0 VOLTS		77	336	HOUR	0
		125°C, 7.0 VOLTS		77	1000	HOUR	0
		TOTALS:	FAIL RATE (Fits):	30	DEVICE HRS: 3.07E+07		0
P21279	HIGH TEMP STORAGE	125°C		233	24	HOUR	
	MOISTURE SOAK	85°C/85% R.H.		233	168	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE		233	3	PASS	0
		TOTAL:					0
P21441	TEMP CYCLE	-55 TO 125°C		40	300	CYCL	0
				40	1000	CYCL	0
		TOTAL:					0
P21442	HAST	120°C, 85%R.H.,5.5V		72	100	HOUR	0
		TOTAL:					0
P21443	AUTOCLAVE	121°C STEAM, UNBIASED		40	96	HOUR	0
		TOTAL:					0

RELIABILITY MONITOR

DS1233Z-10 APR '98 MONITOR-CARSEM

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS1233	A5	9752	DM740622ACA	SOT-223	CARSEM

PROCESS Single Poly, Single Metal 1.2 µ Zero tempco poly

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: 60% Tuse: 55 °C
Ea: 0.7 Vuse: 5.5 Volts
β: 1

JOB NO	DESCRIPT	CONDITION		QUANTITY	READPOINT	UNITS	NO OF FAILS
P22075	INFANT LIFE	125°C, 7.0 VOLTS		229	48	HOUR	0
P22185	HIGH VOLTAGE LIFE	125°C, 7.0 VOLTS		77	336	HOUR	0
		125°C, 7.0 VOLTS		77	1000	HOUR	0
		TOTALS:	FAIL RATE (Fits):	30	DEVICE HRS: 3.07E+07		0
P21903	HIGH TEMP STORAGE	125°C		233	24	HOUR	
	MOISTURE SOAK	85°C/85% R.H.		233	168	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE		233	3	PASS	0
		TOTAL:					0
P22186	TEMP CYCLE	-55 TO 125°C		40	300	CYCL	0
				40	1000	CYCL	0
		TOTAL:					0
P22187	HAST	120°C, 85%R.H.,5.5V		72	100	HOUR	0
		TOTAL:					0
P22188	AUTOCLAVE	121°C STEAM, UNBIASED		40	96	HOUR	0
		TOTAL:					0

RELIABILITY MONITOR

DS1267E-50 NOV.'97 MONITOR-ANAM,PI

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS1267	A1	9737	DK727730AAA	20 PIN TSSOP	ANAM-PI (AAPI)

PROCESS Single Poly, Single Metal 1.2 µ Implanted poly1

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: 60% Tuse: 55 °C
Ea: 0.7 Vuse: 5.5 Volts
β: 1

JOB NO	DESCRIPT	CONDITION		QUANTITY	READPOINT	UNITS	NO OF FAILS
P20991	INFANT LIFE	125°C, 6.0V,-4.0V		234	48	HOUR	0
P21102	HIGH VOLTAGE LIFE	125°C, 6.0V,-4.0V		77	336	HOUR	0
		125°C, 6.0V,-4.0V		77	1000	HOUR	0
		TOTALS:	FAIL RATE (Fits):	81	DEVICE HRS: 1.13E+07		0
P20871	HIGH TEMP STORAGE	125°C		238	24	HOUR	
	MOISTURE SOAK	85°C/85% R.H.		238	168	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE		238	3	PASS	0
		TOTAL:					0
P21103	TEMP CYCLE	-55 TO 125°C		40	300	CYCL	0
				40	1000	CYCL	0
		TOTAL:					0
P21104	BIASED MOISTURE	85/85, 5.5 VOLTS		77	274	HOUR	0
				76	959	HOUR	0
		TOTAL:					0
P21105	AUTOCLAVE	121°C STEAM, UNBIASED		40	96	HOUR	0
		TOTAL:					0

RELIABILITY MONITOR

DS1302Z DEC '97 MONITOR-ANAM,K.

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS1302	C1	9745	DN736077AAC	8 PIN SOIC	ANAM-KOREA (AICL)

PROCESS Single Poly, Double Metal 0.8 µ Standard Process

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: 60% Tuse: 55 °C
Ea: 0.7 Vuse: 5.5 Volts
β: 1

JOB NO	DESCRIPT	CONDITION		QUANTITY	READPOINT	UNITS	NO OF FAILS
P21627	INFANT LIFE	125°C, 6.0 VOLTS		232	48	HOUR	0
P21731	HIGH VOLTAGE LIFE	125°C, 6.0 VOLTS		77	336	HOUR	0
		125°C, 6.0 VOLTS		77	1000	HOUR	0
		TOTALS:	FAIL RATE (Fits):	81	DEVICE HRS: 1.13E+07		0
P21228	HIGH TEMP STORAGE	125°C		238	24	HOUR	
	MOISTURE SOAK	85°C/85% R.H.		238	168	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE		238	3	PASS	0
		TOTAL:					0
P21732	TEMP CYCLE	-55 TO 125°C		40	300	CYCL	0
				40	1000	CYCL	0
		TOTAL:					0
P21733	BIASED MOISTURE	85/85, 5.5 VOLTS		74	274	HOUR	0
				74	959	HOUR	0
		TOTAL:					0
P21734	AUTOCLAVE	121°C STEAM, UNBIASED		40	96	HOUR	0
		TOTAL:					0

RELIABILITY MONITOR

DS1302Z MAR '98 MONITOR-HYUNDAI,K.

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS1302	C1	9808	DL750312ABA	8 PIN SOIC	HYUNDAI-KOREA (HEI)

PROCESS Single Poly, Double Metal 0.8 µ Standard Process

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: 60% Tuse: 55 °C
Ea: 0.7 Vuse: 5.5 Volts
β: 1

JOB NO	DESCRIPT	CONDITION		QUANTITY	READPOINT	UNITS	NO OF FAILS
P21826	INFANT LIFE	125°C, 6.0 VOLTS		229	48	HOUR	0
P21972	HIGH VOLTAGE LIFE	125°C, 6.0 VOLTS		75	336	HOUR	0
		125°C, 6.0 VOLTS		75	1000	HOUR	0
		TOTALS:	FAIL RATE (Fits):	83	DEVICE HRS: 1.11E+07		0
P21736	HIGH TEMP STORAGE	125°C		238	24	HOUR	
	MOISTURE SOAK	85°C/85% R.H.		238	168	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE		238	3	PASS	0
		TOTAL:					0
P21973	TEMP CYCLE	-55 TO 125°C		40	300	CYCL	0
				40	1000	CYCL	0
		TOTAL:					0
P21974	BIASED MOISTURE	85/85, 5.5 VOLTS		75	274	HOUR	0
				75	959	HOUR	0
		TOTAL:					0
P21975	AUTOCLAVE	121°C STEAM, UNBIASED		39	96	HOUR	0
		TOTAL:					0

RELIABILITY MONITOR

DS1315 MAR '98 MONITOR-ANAM,PI

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS1315	B1	9803	DK740539AAA	16 PIN PDIP	ANAM-PI (AAPI)

PROCESS Single Poly, Double Metal 0.8 µ Standard Process

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: 60% Tuse: 55 °C
Ea: 0.7 Vuse: 5.5 Volts
β: 1

JOB NO	DESCRIPT	CONDITION		QUANTITY	READPOINT	UNITS	NO OF FAILS
P21737	INFANT LIFE	125°C, 7.0 VOLTS		234	48	HOUR	0
P21792	HIGH VOLTAGE LIFE	125°C, 7.0 VOLTS		65	336	HOUR	0
		125°C, 7.0 VOLTS		65	1000	HOUR	0
		TOTALS:	FAIL RATE (Fits):	35	DEVICE HRS: 2.62E+07		0
P21793	TEMP CYCLE	-55 TO 125°C		40	300	CYCL	0
				40	1000	CYCL	0
		TOTAL:					0
P21794	HAST	120°C, 85%R.H.,5.5V		65	100	HOUR	0
		TOTAL:					0
P21795	AUTOCLAVE	121°C STEAM, UNBIASED		37	96	HOUR	0
		TOTAL:					0

RELIABILITY MONITOR

DS1620S DEC '97 MONITOR-NSEB

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS1620	C1	9740	DJ724413AAD	8PN SOIC, 208MIL	ALPHTK-BANGKOK(NSEB)

PROCESS Single Poly, Single Metal 1.2 µ E2PROM process

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: 60% Tuse: 55 °C
Ea: 0.7 Vuse: 5.5 Volts
β: 1

JOB NO	DESCRIPT	CONDITION		QUANTITY	READPOINT	UNITS	NO OF FAILS
P21529	INFANT LIFE	125°C, 7.0 VOLTS		237	48	HOUR	0
P21852	HIGH VOLTAGE LIFE	125°C, 7.0 VOLTS		77	336	HOUR	0
		125°C, 7.0 VOLTS		77	1000	HOUR	0
		TOTALS:	FAIL RATE (Fits):	30	DEVICE HRS: 3.09E+07		0
P21254	HIGH TEMP STORAGE	125°C		241	24	HOUR	
	MOISTURE SOAK	85°C/85% R.H.		241	168	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE		241	3	PASS	0
		TOTAL:					0
P21853	TEMP CYCLE	-55 TO 125°C		40	300	CYCL	0
				40	1000	CYCL	0
		TOTAL:					0
P21854	HAST	120°C, 85%R.H.,5.5V		70	100	HOUR	0
		TOTAL:					0
P22149	HIGH TEMP STORAGE	150°C		49	336	HOUR	0
				49	1000	HOUR	0
		ELEC TEST		49	1000	HOUR	0
		TOTAL:					0

RELIABILITY MONITOR

DS1620 JUN '98 MONITOR - NSEB

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS1620	D1	9741	DJ723284AAF	8PN SOIC, 208MIL	ALPHTK-BANGKOK(NSEB)

PROCESS Single Poly, Single Metal 0.8 µ E2PROM process

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: 60% Tuse: 55 °C
Ea: 0.7 Vuse: 5.5 Volts
β: 1

JOB NO	DESCRIPT	CONDITION		QUANTITY	READPOINT	UNITS	NO OF FAILS
P22198	INFANT LIFE	125°C, 7.0 VOLTS		237	48	HOUR	0
		TOTALS:	FAIL RATE (Fits):	231	DEVICE HRS: 3.96E+06		0
P22129	HIGH TEMP STORAGE	125°C		241	24	HOUR	
	MOISTURE SOAK	85°C/85% R.H.		241	168	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE		241	3	PASS	0
		TOTAL:					0
P22289	HAST	120°C, 85%R.H.,5.5V		70	100	HOUR	0
		TOTAL:					0

RELIABILITY MONITOR

DS1620 MAR '98 MONITOR - NSEB

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS1620	C1	9746	DJ723286AAC	8PN SOIC, 208MIL	ALPHTK-BANGKOK(NSEB)

PROCESS Single Poly, Single Metal 1.2 µ E2PROM process

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: 60% Tuse: 55 °C
Ea: 0.7 Vuse: 5.5 Volts
β: 1

JOB NO	DESCRIPT	CONDITION		QUANTITY	READPOINT	UNITS	NO OF FAILS
P22173	INFANT LIFE	125°C, 7.0 VOLTS		232	48	HOUR	0
		TOTALS:	FAIL RATE (Fits):	235	DEVICE HRS: 3.89E+06		0
P22067	HIGH TEMP STORAGE	125°C		236	24	HOUR	
	MOISTURE SOAK	85°C/85% R.H.		236	168	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE		236	3	PASS	0
		TOTAL:					0
P22273	HAST	120°C, 85%R.H.,5.5V		70	100	HOUR	0
		TOTAL:					0

RELIABILITY MONITOR

DS1621S DEC '97 MONITOR-CARSEM

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS1621	A5	9740	DM727709AAA	8 PIN SOIC	CARSEM

PROCESS Single Poly, Single Metal 0.8 µ E2PROM process

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: 60% Tuse: 55 °C
Ea: 0.7 Vuse: 5.5 Volts
β: 1

JOB NO	DESCRIPT	CONDITION		QUANTITY	READPOINT	UNITS	NO OF FAILS
P21367	INFANT LIFE	125°C, 7.0 VOLTS		236	48	HOUR	0
P21727	HIGH VOLTAGE LIFE	125°C, 7.0 VOLTS		77	336	HOUR	0
		125°C, 7.0 VOLTS		77	1000	HOUR	0
		TOTALS:	FAIL RATE (Fits):	30	DEVICE HRS: 3.08E+07		0
P21256	HIGH TEMP STORAGE	125°C		241	24	HOUR	
	MOISTURE SOAK	85°C/85% R.H.		241	168	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE		241	3	PASS	0
		TOTAL:					0
P21728	TEMP CYCLE	-55 TO 125°C		40	300	CYCL	0
				39	1000	CYCL	0
		TOTAL:					0
P21729	BIASED MOISTURE	85/85, 5.5 VOLTS		65	274	HOUR	0
				65	959	HOUR	0
		TOTAL:					0
P22121	HIGH TEMP STORAGE	150°C		50	336	HOUR	0
				50	1000	HOUR	0
		ELEC TEST		50	1000	HOUR	0
		TOTAL:					0

RELIABILITY MONITOR

DS1621 JUN '98 MONITOR-CARSEM

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS1621	A5	9745	DM734572AAD	8 PIN SOIC	CARSEM

PROCESS Single Poly, Single Metal 0.8 µ E2PROM process

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: 60%
Ea: 0.7
β: 1

Tuse: 55 °C
Vuse: 5.5 Volts

JOB NO	DESCRIPT	CONDITION		QUANTITY	READPOINT	UNITS	NO OF FAILS
P22200	INFANT LIFE	125°C, 7.0 VOLTS		237	48	HOUR	0
		TOTALS:	FAIL RATE (Fits):	232	DEVICE HRS: 3.94E+06		0
P22131	HIGH TEMP STORAGE	125°C		241	24	HOUR	
	MOISTURE SOAK	85°C/85% R.H.		241	168	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE		241	3	PASS	0
		TOTAL:					0

RELIABILITY MONITOR

DS1669S-10 NOV.'97 MONITOR-OMEDATA

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS1669	B3	9744	DD650016AAA	8PN SOIC, 208MIL	OMEDATA

PROCESS Single Poly, Single Metal 1.2 µ E2PROM process

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: 60% Tuse: 55 °C
Ea: 0.7 Vuse: 5.5 Volts
β: 1

JOB NO	DESCRIPT	CONDITION		QUANTITY	READPOINT	UNITS	NO OF FAILS
P21187	INFANT LIFE	125°C, 7.0 VOLTS		232	48	HOUR	0
		ELEC TEST		38	48	HOUR	0
P21819	HIGH VOLTAGE LIFE	125°C, 7.0 VOLTS		77	336	HOUR	0
		125°C, 7.0 VOLTS		76	1000	HOUR	0
		TOTALS:	FAIL RATE (Fits):	30	DEVICE HRS: 3.04E+07		0
P20997	HIGH TEMP STORAGE	125°C		238	24	HOUR	
	MOISTURE SOAK	85°C/85% R.H.		238	168	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE		238	3	PASS	0
		TOTAL:					0
P21820	TEMP CYCLE	-55 TO 125°C		40	300	CYCL	0
				35	1000	CYCL	0
		TOTAL:					0
P21821	BIASED MOISTURE	85/85, 5.5 VOLTS		73	274	HOUR	0
				69	959	HOUR	0
		TOTAL:					0
P21822	HIGH TEMP STORAGE	150°C		38	336	HOUR	0
				36	1000	HOUR	0
		ELEC TEST		36	1000	HOUR	0

RELIABILITY MONITOR

DS1669S-10 NOV.'97 MONITOR-OMEDATA

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS1669	B3	9744	DD650016AAA	8PN SOIC, 208MIL	OMEDATA

PROCESS Single Poly, Single Metal 1.2 µ E2PROM process

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: 60%
Ea: 0.7
β: 1

Tuse: 55 °C
Vuse: 5.5 Volts

JOB NO	DESCRIPT	CONDITION	QUANTITY	READPOINT	UNITS	NO OF FAILS
		TOTAL:				0

RELIABILITY MONITOR

DS17485 FEB.'98 MONITOR,D.P.-ANAM,K

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS17485	A2	9730	DN713701AAE	24 PIN SOIC	ANAM-KOREA (AICL)

PROCESS Single Poly, Double Metal 0.8 µ Standard Process

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: 60% Tuse: 55 °C
Ea: 0.7 Vuse: 5.5 Volts
β: 1

JOB NO	DESCRIPT	CONDITION		QUANTITY	READPOINT	UNITS	NO OF FAILS
P22032	INFANT LIFE	125°C, 7.0 VOLTS		230	48	HOUR	0
		TOTALS:	FAIL RATE (Fits):	241	DEVICE HRS: 3.81E+06		0
P21607	HIGH TEMP STORAGE	125°C		237	24	HOUR	
	MOISTURE SOAK	30°C/60% R.H.		237	144	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE		237	3	PASS	0
		TOTAL:					0
P22305	HAST	120°C, 85%R.H.,5.5V		63	100	HOUR	0
		TOTAL:					0
P22306	AUTOCLAVE	121°C STEAM, UNBIASED		40	96	HOUR	0
		TOTAL:					0

RELIABILITY MONITOR

DS17485 MAY '98 MONITOR,D.P-ANAM,K.

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS17485	A2	9814	DN803023AAD	24 PIN SOIC	ANAM-KOREA (AICL)

PROCESS Single Poly, Double Metal 0.8 µ Standard Process

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: 60%
Ea: 0.7
β: 1

Tuse: 55 °C
Vuse: 5.5 Volts

JOB NO	DESCRIPT	CONDITION		QUANTITY	READPOINT	UNITS	NO OF FAILS
P22308	INFANT LIFE	125°C, 7.0 VOLTS		230	48	HOUR	0
		TOTALS:	FAIL RATE (Fits):	239	DEVICE HRS: 3.84E+06		0
P22010	HIGH TEMP STORAGE	125°C		237	24	HOUR	
	MOISTURE SOAK	30°C/60% R.H.		237	144	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE		237	3	PASS	0
		TOTAL:					0

RELIABILITY MONITOR

DS2108 FEB.'98 MONITOR,D.P.-ANAM,K.

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS2108	B1	9740	DN729120AAC	24 PIN SOIC	ANAM-KOREA (AICL)

PROCESS Single Poly, Single Metal 5.0 µ Negative zero tempco poly

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: 60% Tuse: 55 °C
Ea: 0.7 Vuse: 5.5 Volts
β: 1

JOB NO	DESCRIPT	CONDITION		QUANTITY	READPOINT	UNITS	NO OF FAILS
P21556	INFANT LIFE	125°C, 7.0 VOLTS		234	48	HOUR	0
P21690	HIGH VOLTAGE LIFE	125°C, 6.0 VOLTS		77	336	HOUR	0
		125°C, 6.0 VOLTS		77	1000	HOUR	0
		TOTALS:	FAIL RATE (Fits):	66	DEVICE HRS: 1.38E+07		0
P21471	HIGH TEMP STORAGE	125°C		238	24	HOUR	
	MOISTURE SOAK	85°C/85% R.H.		238	168	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE		238	3	PASS	0
		TOTAL:					0
P21691	TEMP CYCLE	-55 TO 125°C		40	300	CYCL	0
				40	1000	CYCL	0
		TOTAL:					0
P21692	BIASED MOISTURE	85/85, 5.5 VOLTS		77	274	HOUR	0
				77	959	HOUR	0
		TOTAL:					0
P21693	AUTOCLAVE	121°C STEAM, UNBIASED		40	96	HOUR	0
		TOTAL:					0

RELIABILITY MONITOR

DS2108 MAY '98 MONITOR,D.P-ANAM,K.

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS2108	B1	9741	DN729121ABA	24 PIN SOIC	ANAM-KOREA (AICL)

PROCESS Single Poly, Single Metal 5.0 µ Negative zero tempco poly

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: 60% Tuse: 55 °C
Ea: 0.7 Vuse: 5.5 Volts
β: 1

JOB NO	DESCRIPT	CONDITION		QUANTITY	READPOINT	UNITS	NO OF FAILS
P22138	INFANT LIFE	125°C, 6.0 VOLTS		234	48	HOUR	0
P22153	HIGH VOLTAGE LIFE	125°C, 6.0 VOLTS		77	336	HOUR	0
		125°C, 6.0 VOLTS		77	1000	HOUR	0
		TOTALS:	FAIL RATE (Fits):	81	DEVICE HRS: 1.13E+07		0
P22012	HIGH TEMP STORAGE	125°C		238	24	HOUR	
	MOISTURE SOAK	30°C/60% R.H.		238	144	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE		238	3	PASS	0
		TOTAL:					0
P22154	TEMP CYCLE	-55 TO 125°C		40	300	CYCL	0
				40	1000	CYCL	0
		TOTAL:					0
P22155	BIASED MOISTURE	85/85, 5.5 VOLTS		77	274	HOUR	0
				77	959	HOUR	0
		TOTAL:					0
P22156	AUTOCLAVE	121°C STEAM, UNBIASED		39	98	HOUR	0
		TOTAL:					0

RELIABILITY MONITOR

DS2153 JUN '98 MONITOR-ANAM,K

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS2153	A7	9740	DN725561AAB	44 PIN PLCC	ANAM-KOREA (AICL)

PROCESS Double Poly, Single Metal 0.8 µ Capacitor

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: 60% Tuse: 55 °C
Ea: 0.7 Vuse: 5.5 Volts
β: 1

JOB NO	DESCRIPT	CONDITION		QUANTITY	READPOINT	UNITS	NO OF FAILS
P22294	INFANT LIFE	125°C, 6.0 VOLTS		237	48	HOUR	0
		TOTALS:	FAIL RATE (Fits):	629	DEVICE HRS: 1.46E+06		0
P22133	HIGH TEMP STORAGE	125°C		241	24	HOUR	
	MOISTURE SOAK	30°C/60% R.H.		241	144	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE		241	3	PASS	0
		TOTAL:					0
P22336	AUTOCLAVE	121°C STEAM, UNBIASED		100	96	HOUR	0
		TOTAL:					0

RELIABILITY MONITOR

DS2153Q MAR '98 MONITOR,D.P.-ANAM,K.

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS2153	A7	9734	DN720030AAB	44 PIN PLCC	ANAM-KOREA (AICL)

PROCESS Double Poly, Single Metal 0.8 µ Capacitor

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: 60% Tuse: 55 °C
Ea: 0.7 Vuse: 5.5 Volts
β: 1

JOB NO	DESCRIPT	CONDITION		QUANTITY	READPOINT	UNITS	NO OF FAILS
P22292	INFANT LIFE	125°C, 6.0 VOLTS		237	48	HOUR	0
		TOTALS:	FAIL RATE (Fits):	627	DEVICE HRS: 1.46E+06		0
P21818	HIGH TEMP STORAGE	125°C		241	24	HOUR	
	MOISTURE SOAK	30°C/60% R.H.		241	144	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE		241	3	PASS	0
		TOTAL:					0
P22333	AUTOCLAVE	121°C STEAM, UNBIASED		100	96	HOUR	0
		TOTAL:					0

RELIABILITY MONITOR

DS2175S JAN '98 MONITOR-ANAM,K.

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS2175S	D1	9745	DN736121AAE	16 PIN SOIC	ANAM-KOREA (AICL)

PROCESS Single Poly, Single Metal 2.0 µ Pfield

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: 60% Tuse: 55 °C
Ea: 0.7 Vuse: 5.5 Volts
β: 1

JOB NO	DESCRIPT	CONDITION		QUANTITY	READPOINT	UNITS	NO OF FAILS
P21487	INFANT LIFE	125°C, 7.0 VOLTS		234	48	HOUR	0
P21612	HIGH VOLTAGE LIFE	125°C, 7.0 VOLTS		77	336	HOUR	0
		125°C, 7.0 VOLTS		77	1000	HOUR	0
		TOTALS:	FAIL RATE (Fits):	30	DEVICE HRS: 3.08E+07		0
P21340	TEMP CYCLE	-55 TO 125°C		238	10	CYCL	
	HIGH TEMP STORAGE	125°C		238	24	HOUR	
	MOISTURE SOAK	85°C/85% R.H.		238	168	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE		238	3	PASS	0
		TOTAL:					0
P21613	TEMP CYCLE	-55 TO 125°C		40	300	CYCL	0
				40	1000	CYCL	0
		TOTAL:					0
P21614	BIASED MOISTURE	85/85, 5.5 VOLTS		77	274	HOUR	0
				77	959	HOUR	0
		TOTAL:					0
P21615	AUTOCLAVE	121°C STEAM, UNBIASED		40	96	HOUR	0
		TOTAL:					0

RELIABILITY MONITOR

DS2180A NOV.'97 MONITOR-ANAM,K.

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS2180A	B3	9734	DN725581AAC	44 PIN PLCC	ANAM-KOREA (AICL)

PROCESS Single Poly, Single Metal 2.0 µ Pfield

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: 60% Tuse: 55 °C
Ea: 0.7 Vuse: 5.5 Volts
β: 1

JOB NO	DESCRIPT	CONDITION		QUANTITY	READPOINT	UNITS	NO OF FAILS
P20995	INFANT LIFE	125°C, 7.0 VOLTS		235	48	HOUR	0
P21121	HIGH VOLTAGE LIFE	125°C, 7.0 VOLTS		77	336	HOUR	0
		125°C, 7.0 VOLTS		77	1000	HOUR	0
		TOTALS:	FAIL RATE (Fits):	30	DEVICE HRS: 3.08E+07		0
P20941	TEMP CYCLE	-55 TO 125°C		241	10	CYCL	
	HIGH TEMP STORAGE	125°C		241	24	HOUR	
	MOISTURE SOAK	30°C/60% R.H.		241	144	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE		241	3	PASS	0
		TOTAL:					0
P21122	TEMP CYCLE	-55 TO 125°C		60	300	CYCL	0
				59	1000	CYCL	0
		TOTAL:					0
P21123	HAST	120°C, 85%R.H.,5.5V		60	100	HOUR	1
		TOTAL:					1
P21124	AUTOCLAVE	121°C STEAM, UNBIASED		38	96	HOUR	0
		TOTAL:					0

JOB NO	FAILURE MODE	FAILURE MECHANISM	CORRECTIVE ACTION
P21123	IDD	IN PROCESS	

RELIABILITY MONITOR

DS2180A MAY '98 MONITOR-ANAM,K.

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS2180A	B3	9810	DN752567AAB	44 PIN PLCC	ANAM-KOREA (AICL)

PROCESS Single Poly, Single Metal 2.0 µ Pfield

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: 60% Tuse: 55 °C
Ea: 0.7 Vuse: 5.5 Volts
β: 1

JOB NO	DESCRIPT	CONDITION		QUANTITY	READPOINT	UNITS	NO OF FAILS
P22196	INFANT LIFE	125°C, 7.0 VOLTS		236	48	HOUR	0
		TOTALS:	FAIL RATE (Fits):	231	DEVICE HRS: 3.96E+06		0
P22014	TEMP CYCLE	-55 TO 125°C		241	10	CYCL	
	HIGH TEMP STORAGE	125°C		241	24	HOUR	
	MOISTURE SOAK	30°C/60% R.H.		241	144	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE		241	3	PASS	0
		TOTAL:					0
P22279	HAST	120°C, 85%R.H.,5.5V		59	100	HOUR	0
		TOTAL:					0
P22280	AUTOCLAVE	121°C STEAM, UNBIASED		39	96	HOUR	0
		TOTAL:					0

RELIABILITY MONITOR

DS2181A FEB.'98 MONITOR-ANAM,K.

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS2181A	A2	9741	DN728030AAB	44 PIN PLCC	ANAM-KOREA (AICL)

PROCESS Single Poly, Single Metal 2.0 µ Pfield

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: 60% Tuse: 55 °C
Ea: 0.7 Vuse: 5.5 Volts
β: 1

JOB NO	DESCRIPT	CONDITION		QUANTITY	READPOINT	UNITS	NO OF FAILS
P21699	INFANT LIFE	125°C, 7.0 VOLTS		237	48	HOUR	0
P21777	HIGH VOLTAGE LIFE	125°C, 7.0 VOLTS		77	336	HOUR	0
		125°C, 7.0 VOLTS		77	1000	HOUR	0
		TOTALS:	FAIL RATE (Fits):	30	DEVICE HRS: 3.09E+07		0
P21493	TEMP CYCLE	-55 TO 125°C		241	10	CYCL	
	HIGH TEMP STORAGE	125°C		241	24	HOUR	
	MOISTURE SOAK	30°C/60% R.H.		241	144	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE		241	3	PASS	0
		TOTAL:					0
P21778	TEMP CYCLE	-55 TO 125°C		60	300	CYCL	0
				60	1000	CYCL	0
		TOTAL:					0
P21779	HAST	120°C, 85%R.H.,5.5V		60	100	HOUR	0
		TOTAL:					0
P21780	AUTOCLAVE	121°C STEAM, UNBIASED		40	96	HOUR	0
		TOTAL:					0

RELIABILITY MONITOR

DS21S07A FEB '98 MONITOR-CARSEM

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS21S07	E	9802	DM741735ABC	20 PIN TSSOP	CARSEM

PROCESS Single Poly, Single Metal 0.8 µ Negative zero tempco poly

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: 60% Tuse: 55 °C
Ea: 0.7 Vuse: 5.5 Volts
β: 1

JOB NO	DESCRIPT	CONDITION		QUANTITY	READPOINT	UNITS	NO OF FAILS
P21637	INFANT LIFE	125°C, 7.0 VOLTS		234	48	HOUR	0
P21694	HIGH VOLTAGE LIFE	125°C, 7.0 VOLTS		77	336	HOUR	0
		125°C, 7.0 VOLTS		77	1000	HOUR	0
		TOTALS:	FAIL RATE (Fits):	30	DEVICE HRS: 3.08E+07		0
P21469	HIGH TEMP STORAGE	125°C		238	24	HOUR	
	MOISTURE SOAK	85°C/85% R.H.		238	168	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE		238	3	PASS	0
		TOTAL:					0
P21695	TEMP CYCLE	-55 TO 125°C		40	300	CYCL	0
				40	1000	CYCL	0
		TOTAL:					0
P21696	BIASED MOISTURE	85/85, 5.5 VOLTS		77	274	HOUR	0
				77	959	HOUR	0
		TOTAL:					0
P21697	AUTOCLAVE	121°C STEAM, UNBIASED		40	96	HOUR	0
		TOTAL:					0

RELIABILITY MONITOR

DS21S07A MAY '98 MONITOR-CARSEM

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS21S07	E	9815	DM805323AAE	20 PIN TSSOP	CARSEM

PROCESS Single Poly, Single Metal 0.8 µ Negative zero tempco poly

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: 60% Tuse: 55 °C
Ea: 0.7 Vuse: 5.5 Volts
β: 1

JOB NO	DESCRIPT	CONDITION		QUANTITY	READPOINT	UNITS	NO OF FAILS
P22171	INFANT LIFE	125°C, 7.0 VOLTS		234	48	HOUR	0
P22242	HIGH VOLTAGE LIFE	125°C, 7.0 VOLTS		77	336	HOUR	0
		125°C, 7.0 VOLTS		77	1000	HOUR	0
		TOTALS:	FAIL RATE (Fits):	30	DEVICE HRS: 3.08E+07		0
P22102	HIGH TEMP STORAGE	125°C		238	24	HOUR	
	MOISTURE SOAK	85°C/85% R.H.		238	168	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE		238	3	PASS	0
		TOTAL:					0
P22243	TEMP CYCLE	-55 TO 125°C		40	300	CYCL	0
				40	1000	CYCL	0
		TOTAL:					0
P22245	AUTOCLAVE	121°C STEAM, UNBIASED		40	96	HOUR	0
		TOTAL:					0

RELIABILITY MONITOR

DS232 JUN '98 MONITOR - OMEDATA

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS232	B3	9809	DD747723ABD	16 PIN PDIP	OMEDATA

PROCESS Single Poly, Single Metal 5.0 µ Standard Process

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: 60% Tuse: 55 °C
Ea: 0.7 Vuse: 5.5 Volts
β: 1

JOB NO	DESCRIPT	CONDITION		QUANTITY	READPOINT	UNITS	NO OF FAILS
P22122	INFANT LIFE	125°C, 7.0 VOLTS		234	48	HOUR	0
		TOTALS:	FAIL RATE (Fits):	233	DEVICE HRS: 3.92E+06		0
P22167	TEMP CYCLE	-55 TO 125°C		40	300	CYCL	0
				40	1000	CYCL	0
		TOTAL:					0
P22169	AUTOCLAVE	121°C STEAM, UNBIASED		40	96	HOUR	0
		TOTAL:					0

RELIABILITY MONITOR

DS232 MAR '98 MONITOR-OMEDATA

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS232	B3	9809	DD747723AAB	16 PIN PDIP	OMEDATA

PROCESS Single Poly, Single Metal 5.0 µ Standard Process

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: 60% Tuse: 55 °C
Ea: 0.7 Vuse: 5.5 Volts
β: 1

JOB NO	DESCRIPT	CONDITION		QUANTITY	READPOINT	UNITS	NO OF FAILS
P21726	INFANT LIFE	125°C, 7.0 VOLTS		234	48	HOUR	0
P21751	HIGH VOLTAGE LIFE	125°C, 7.0 VOLTS		77	336	HOUR	0
		125°C, 7.0 VOLTS		77	1000	HOUR	0
		TOTALS:	FAIL RATE (Fits):	30	DEVICE HRS: 3.08E+07		0
P21752	TEMP CYCLE	-55 TO 125°C		40	300	CYCL	0
				40	1000	CYCL	0
		TOTAL:					0
P21753	BIASED MOISTURE	85/85, 5.5 VOLTS		77	274	HOUR	0
				77	959	HOUR	0
		TOTAL:					0
P21754	AUTOCLAVE	121°C STEAM, UNBIASED		40	96	HOUR	0
		TOTAL:					0

RELIABILITY MONITOR

DS2401 MAR '98 MONITOR-CARSEM

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS2401	B2	9802	DM741755ACA	T0-92	CARSEM

PROCESS Single Poly, Single Metal 0.8 µ Standard Process

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: 60% Tuse: 55 °C
Ea: 0.7 Vuse: 5.5 Volts
β: 1

JOB NO	DESCRIPT	CONDITION		QUANTITY	READPOINT	UNITS	NO OF FAILS
P22162	HIGH VOLTAGE LIFE	125°C, 7.0 VOLTS		77	336	HOUR	0
		125°C, 7.0 VOLTS		77	1000	HOUR	0
		TOTALS:	FAIL RATE (Fits):	34	DEVICE HRS: 2.69E+07		0
P22163	TEMP CYCLE	-55 TO 125°C		40	300	CYCL	0
				40	1000	CYCL	0
		TOTAL:					0
P22164	HAST	120°C, 85%R.H.,5.5V		77	100	HOUR	0
		TOTAL:					0
P22165	AUTOCLAVE	121°C STEAM, UNBIASED		39	96	HOUR	0
		TOTAL:					0

RELIABILITY MONITOR

DS2401 MAR '98 MONITOR-CARSEM

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS2401	B2	9802	DM741755ACA	T0-92	CARSEM

PROCESS Single Poly, Single Metal 0.8 µ Standard Process

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: 60% Tuse: 55 °C
Ea: 0.7 Vuse: 5.5 Volts
β: 1

JOB NO	DESCRIPT	CONDITION		QUANTITY	READPOINT	UNITS	NO OF FAILS
P22152	INFANT LIFE	125°C, 7.0 VOLTS		234	48	HOUR	0
		TOTALS:	FAIL RATE (Fits):	234	DEVICE HRS: 3.91E+06		0
P22163	TEMP CYCLE	-55 TO 125°C		40	300	CYCL	0
				40	1000	CYCL	0
		TOTAL:					0
P22164	HAST	120°C, 85%R.H.,5.5V		77	100	HOUR	0
		TOTAL:					0
P22165	AUTOCLAVE	121°C STEAM, UNBIASED		39	96	HOUR	0
		TOTAL:					0

RELIABILITY MONITOR

DS2401 JUN '98 MONITOR-CARSEM

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS2401	B2	9805	DM743297ADA	T0-92	CARSEM

PROCESS Single Poly, Single Metal 0.8 µ Standard Process

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: 60% Tuse: 55 °C
Ea: 0.7 Vuse: 5.5 Volts
β: 1

JOB NO	DESCRIPT	CONDITION		QUANTITY	READPOINT	UNITS	NO OF FAILS
P22123	INFANT LIFE	125°C, 7.0 VOLTS		234	48	HOUR	0
P22157	HIGH VOLTAGE LIFE	125°C, 7.0 VOLTS		77	336	HOUR	0
		125°C, 7.0 VOLTS		77	1000	HOUR	0
		TOTALS:	FAIL RATE (Fits):	30	DEVICE HRS: 3.08E+07		0
P22158	TEMP CYCLE	-55 TO 125°C		40	300	CYCL	0
				40	1000	CYCL	0
		TOTAL:					0
P22159	HAST	120°C, 85%R.H.,5.5V		77	100	HOUR	0
		TOTAL:					0
P22160	AUTOCLAVE	121°C STEAM, UNBIASED		39	96	HOUR	0
		TOTAL:					0

RELIABILITY MONITOR

DS2502 JUN '98 MONITOR - CARSEM

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS2502	B4	9814	DM751356AFA	8 PIN SOIC	CARSEM

PROCESS Single Poly, Single Metal 0.8 µ EPROM process

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: 60% Tuse: 55 °C
Ea: 0.7 Vuse: 5.5 Volts
β: 1

JOB NO	DESCRIPT	CONDITION		QUANTITY	READPOINT	UNITS	NO OF FAILS
P22251	INFANT LIFE	125°C, 7.0 VOLTS		193	48	HOUR	0
		TOTALS:	FAIL RATE (Fits):	283	DEVICE HRS: 3.24E+06		0
P22135	HIGH TEMP STORAGE	125°C		238	24	HOUR	
	MOISTURE SOAK	85°C/85% R.H.		238	168	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE		238	3	PASS	0
	ELECTRICAL TEST	ELEC TEST		238	0		0
		TOTAL:					0
P22298	TEMP CYCLE	-55 TO 125°C		40	300	CYCL	0
				40	1000	CYCL	0
		TOTAL:					0

RELIABILITY MONITOR

DS5002 APR 98 'MONITOR,DP.- CARSEM

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS5002	B3	9806	DM743264AAC	80 PIN PQFP	CARSEM

PROCESS Single Poly, Single Metal 1.2 µ Buried contacts w/silicided poly

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: 60% Tuse: 55 °C
Ea: 0.7 Vuse: 5.5 Volts
β: 1

JOB NO	DESCRIPT	CONDITION		QUANTITY	READPOINT	UNITS	NO OF FAILS
P22249	INFANT LIFE	125°C, 7.0 VOLTS		199	48	HOUR	0
		TOTALS:	FAIL RATE (Fits):	275	DEVICE HRS: 3.34E+06		0
P21907	HIGH TEMP STORAGE	125°C		203	24	HOUR	
	MOISTURE SOAK	30°C/60% R.H.		203	144	HOUR	
	SOLDER HEAT	HTC VAPOR PHASE		203	3	PASS	0
		TOTAL:					0
P22322	AUTOCLAVE	121°C STEAM, UNBIASED		40	96	HOUR	0
		TOTAL:					0

RELIABILITY MONITOR

DS80320 JAN '98 MONITOR-ANAM PI

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS80320	B5	9749	DK739467AAA	40 PIN PDIP	ANAM-PI (AAPI)

PROCESS Single Poly, Single Metal 0.8 µ Poly silicide

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: 60% Tuse: 55 °C
Ea: 0.7 Vuse: 5.5 Volts
β: 1

JOB NO	DESCRIPT	CONDITION		QUANTITY	READPOINT	UNITS	NO OF FAILS
P21300	INFANT LIFE	125°C, 7.0 VOLTS		234	48	HOUR	0
P21353	HIGH VOLTAGE LIFE	125°C, 7.0 VOLTS		77	336	HOUR	0
		125°C, 7.0 VOLTS		77	1000	HOUR	0
		TOTALS:	FAIL RATE (Fits):	30	DEVICE HRS: 3.08E+07		0
P21354	TEMP CYCLE	-55 TO 125°C		40	300	CYCL	0
				40	1000	CYCL	0
		TOTAL:					0
P21355	BIASED MOISTURE	85/85, 5.5 VOLTS		77	274	HOUR	0
				77	959	HOUR	1
		TOTAL:					1
P21356	AUTOCLAVE	121°C STEAM, UNBIASED		40	96	HOUR	0
		TOTAL:					0

JOB NO	FAILURE MODE	FAILURE MECHANISM	CORRECTIVE ACTION
P21355	ICCSP_IN	IN PROCESS	

RELIABILITY MONITOR

DS80320 APR '98 MONITOR-ANAM,PI

DEVICE	REVISION	DATE CODE	LOT NUMBER	PACKAGE	ASSEMBLY SITE
DS80320	B5	9810	DK748103AAB	40 PIN PDIP	ANAM-PI (AAPI)

PROCESS Single Poly, Single Metal 0.8 µ Poly silicide

Summary Data with Chi-Square Distribution Assumed.
Stress Ambient Temperature and Voltage to
Field Ambient Temperature And Voltage

Cf: 60%
Ea: 0.7
β: 1

Tuse: 55 °C
Vuse: 5.5 Volts

JOB NO	DESCRIPT	CONDITION		QUANTITY	READPOINT	UNITS	NO OF FAILS
P21893	INFANT LIFE	125°C, 7.0 VOLTS		234	48	HOUR	0
P21964	HIGH VOLTAGE LIFE	125°C, 7.0 VOLTS		77	336	HOUR	0
		125°C, 7.0 VOLTS		77	1000	HOUR	0
		TOTALS:	FAIL RATE (Fits):	30	DEVICE HRS: 3.07E+07		0
P21965	TEMP CYCLE	-55 TO 125°C		40	300	CYCL	0
				40	1000	CYCL	0
		TOTAL:					0
P21966	BIASED MOISTURE	85/85, 5.5 VOLTS		77	274	HOUR	0
				77	959	HOUR	0
		TOTAL:					0
P21967	AUTOCLAVE	121°C STEAM, UNBIASED		35	96	HOUR	0
		TOTAL:					0